



## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Art Unit: 2131

Serial No.: 10/072,683

Examiner: Gail O. Hayes

Filed Title

: February 8, 2002

: MULTI-METHOD GATEWAY-BASED NETWORK SECURITY SYSTEMS

AND METHODS

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450 RECEIVED

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Technology Center 2100

## INFORMATION DISCLOSURE STATEMENT

Copies of the references listed on the attached form PTO-1449 are enclosed. A copy of a communication from a foreign patent office in a counterpart application is also enclosed.

This statement is being filed within three months of the filing date of the application or before the receipt of a first Office action on the merits. Please apply any charges or credits to Leposit Account No. 06-1050.

Respectfully submitted,

Date:

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Sheet	1	of	1
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Substitute	Form	PTO-1449
(Modified)		

(37 CFR §1.98(b))

U.S. Department of Commerce Patent and Trademark Office Attorney's Docket N-09725-017001

Application No. 10/072,682

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**Information Disclosure Statement** by Applicant (Use several sheets if necessary)

Zuk et al Filing Date

**Applicant** 

February 8, 2002

Group Art UNE

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	6,253,321	6/2001	Nikander et al			
	AB	6,321,338	11/2001	Porras et al			
	AC	6,499,107	12/2002	Gleichauf et al		REC	EIVED
	AD	6,487,666	11/2002	Shanklin et al			
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Initial	ID	Number	Date	Patent Office	Class	Subclass	Yes	No
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Other Documents (include Author, Title, Date, and Place of Publication)				
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**Date Considered** 

EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.